

OTHER DOCUMENTS
(Including Author, Title, Date, Pertinent Pages, Etc.)

<i>✓</i>	C1	International Search Report, PCT
<i>✓</i>	C2	C. Honninger, et al.; <i>Diode-Pumped Thin-Disk Yb: YAG Regenerative Amplifier</i> ; APPLIED PHYSICS B, pp. 423-426
<i>✓</i>	C3	Steven Jackel, et al.; <i>High-Energy Nd:Dr:GSGG Lasers Based on Phase and Polarization Conjugated Multiple-Pass Amplifiers</i> ; OPTICAL ENGINEERING, Vol. 36, No. 7, July 1997, pp. 2031-2036
<i>✓</i>	C4	K. F. Wall, et al.; <i>A Ti:Al₂O₃ Master-Oscillator/Power-Amplifier System</i> ; IEEE JOURNAL OF QUANTUM ELECTRONICS, June 1993, No. 6, pp. 1505-1514

EXAMINER



DATE CONSIDERED

[Handwritten signature] *✓* 2/16/05

Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-213002	Application No. 10/806464
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Peter J. de Groot et al.		
		Filing Date March 22, 2004	Group Art Unit 287	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
SLY	AA	4,743,117	05/1988	Kitabayashi et al.	356	520	
	AB	2003/0043385	03/2003	Kuchel, Michael	356	513	
	AC	2003/0011783	01/2003	Suzuki et al.	356	512	
	AD	5,485,275	01/1996	Ohtsuka, Masaru	356	513	
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AH							
AI							
AJ							
AK							

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature 	Date Considered 2/16/05
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (If Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-213001	Application No. 10/190,353
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Peter de Groot et al.	16180649C
(37 CFR §1.98(b))		Filing Date July 3, 2002	Group Art Unit 2877

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	AB	6,154,279	11/28/2000	Thayer	356	376	
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al	AJ	WO 02/14845	2/21/2002	WIPO	G01N	21/954	
✓	AK	WO 01/75395	10/11/2001	WIPO	G01B	11/30	
✓	AL	WO 01/27558	4/19/2001	WIPO	G01B	11/30	
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Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
al	AO	Boppart et al., "Forward-imaging instruments for optical coherence tomography", <u>Optics Letters</u> , Vol. 22, No. 21, pp. 1618-1620 (November 1, 1997)
✓	AP	Blümel et al., "Absolute interferometric calibration of toric and conical surfaces", <u>SPIE</u> , Vol. 3134, pp. 370-378 (July 1997)
	AQ	Brinkman et al., "Testing of rod objects by grazing-incidence interferometry: experiment", <u>Applied Optics</u> , Vol. 38, No. 1, pp. 121-125 (January 1, 1999)
	AR	Chakmakjian et al., "Simultaneous focus and coherence scanning in interference microscopy", <u>Technical Digest, International Workshop on Interferometry</u> , 171 (Riken, Japan, 1996)
	AS	Dresel et al., "Three-dimensional sensing of rough surfaces by coherence radar", <u>Applied Optics</u> , Vol. 31, No. 7, pp. 919-925 (March 1, 1992)
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Substitute Disclosure Form (PTO-1449)	

Subm Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-213001	Application No. 10/190,353
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Peter de Groot et al.	
(37 CFR §1.98(b))		Filing Date July 3, 2002	Group Art Unit 2877

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
all	BA	Lindner et al., "White-light interferometry via an endoscope", <u>SPIE</u> , Vol. 4777, pp. 90-101 (July 2002)
	BB	Matthys et al., "Panoramic Holointerferometry", <u>Experimental Mechanics</u> , Vol. 35, No. 1, pp. 83-88 (March 1995)
↙	BC	Schwider, "White-light Fizeau interferometer", <u>Applied Optics</u> , Vol. 36, No. 7, pp. 1433-1437 (March 1, 1997)
↙	BD	Zhou et al., "Surface profile measurements using a white light Linnik interferometer", <u>Annual Report Lehrstuhl für Optik, Univ. Erlangen-Nürnberg</u> pp. 69 (1996)
	BE	
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<i>dr</i>	AA	5,293,214	3/8/1994	Ledger	356	355	
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